

Notice of References Cited

Application/Control No.

10/524,729

Applicant(s)/Patent Under
Reexamination
REINSTADTLER ET AL.

Examiner

Daniel S. Larkin

Art Unit

2856

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,852,233	12-1998	Arnold et al.	73/105
*	B	US-6,880,386	04-2005	Krottil et al.	73/105
	C	US-			
	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	S					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Arnold, W. et al.; "Atomic Force Microscopy at Ultrasonic Frequencies", Proceeding International Conference on Non-Destructive Evaluation and Reliability of Micro- and Nanomaterial Systems; International Society for Optical Engineering, SPIE, Vol. 4703, 2002, pp. 53-64.
*	V	Rabe, U. et al.; "Quantitative Determination of Contact Stiffness Using Atomic Force Acoustic Microscopy", Ultrasonics, Vol. 38, 2000, pp. 430-437.
*	W	Yamanaka, K. et al.; "Quantitative Material Characterization by Ultrasonic AFM", Surface and Interface Analysis, Vol. 27, 1999, pp. 600-606.
	X	Rabe, U. et al.; "Probing Linear and Non-linear Tip-Sample Interaction Forces by Atomic Force Acoustic Microscopy", Surface and Interface Analysis, Vol. 27, 1999, pp. 386-391.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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